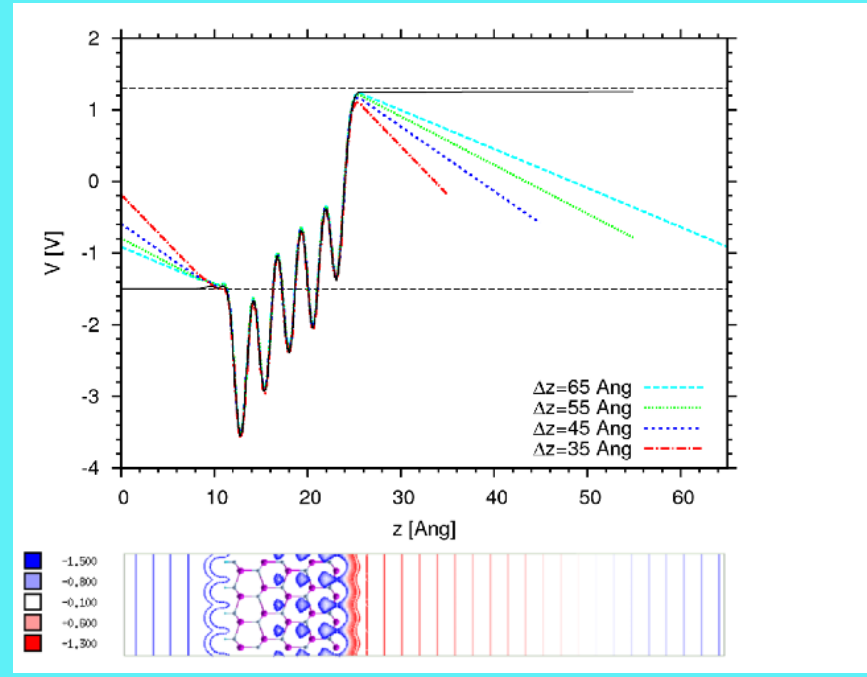


# Charge related phenomena at semiconductor surfaces

P. Strak, P. Kempisty, K. Sakowski, J. Sołtys, J. Piechota, M. Ptasńska, and S. Krukowski

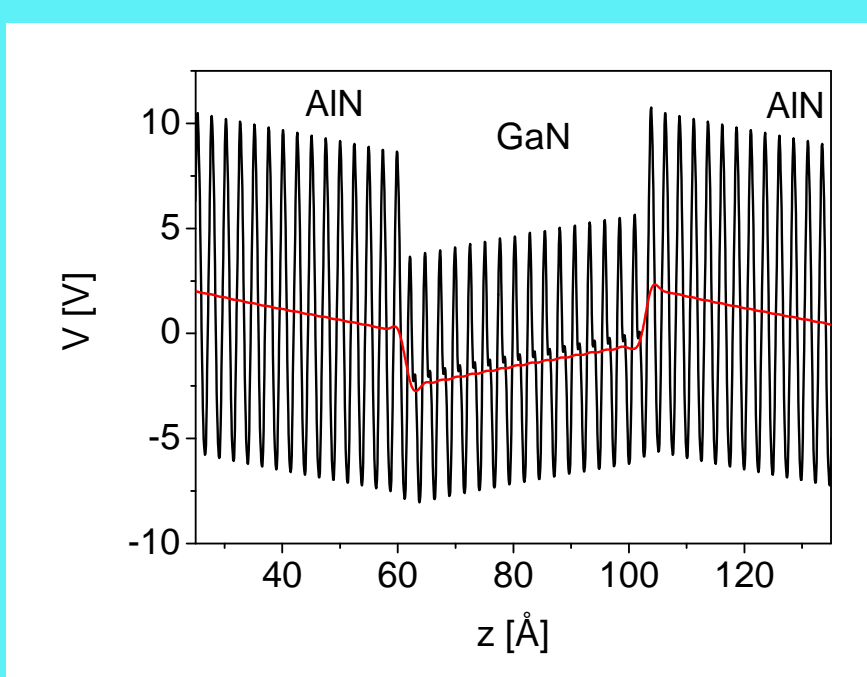
## New methodology – *ab initio* calculations (SIESTA & VASP)

### Laplace correction



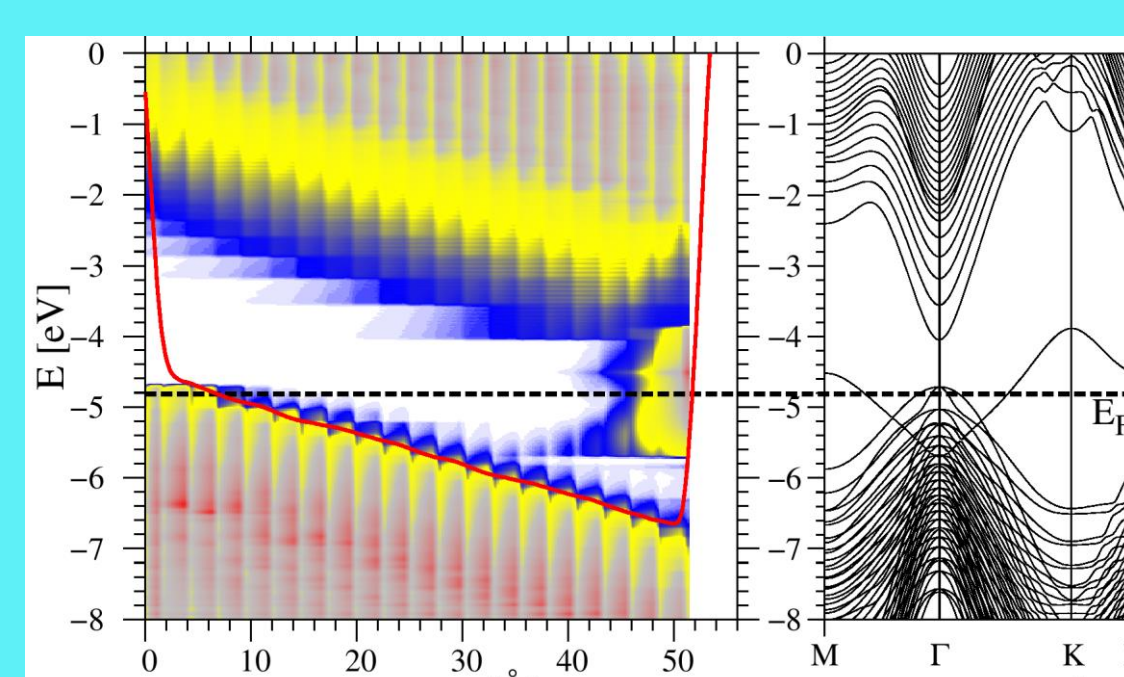
- Laplace equation solution added to Poisson solution equation
- Periodic boundary condition
- No dipole layer in the empty space

### Potential averaging



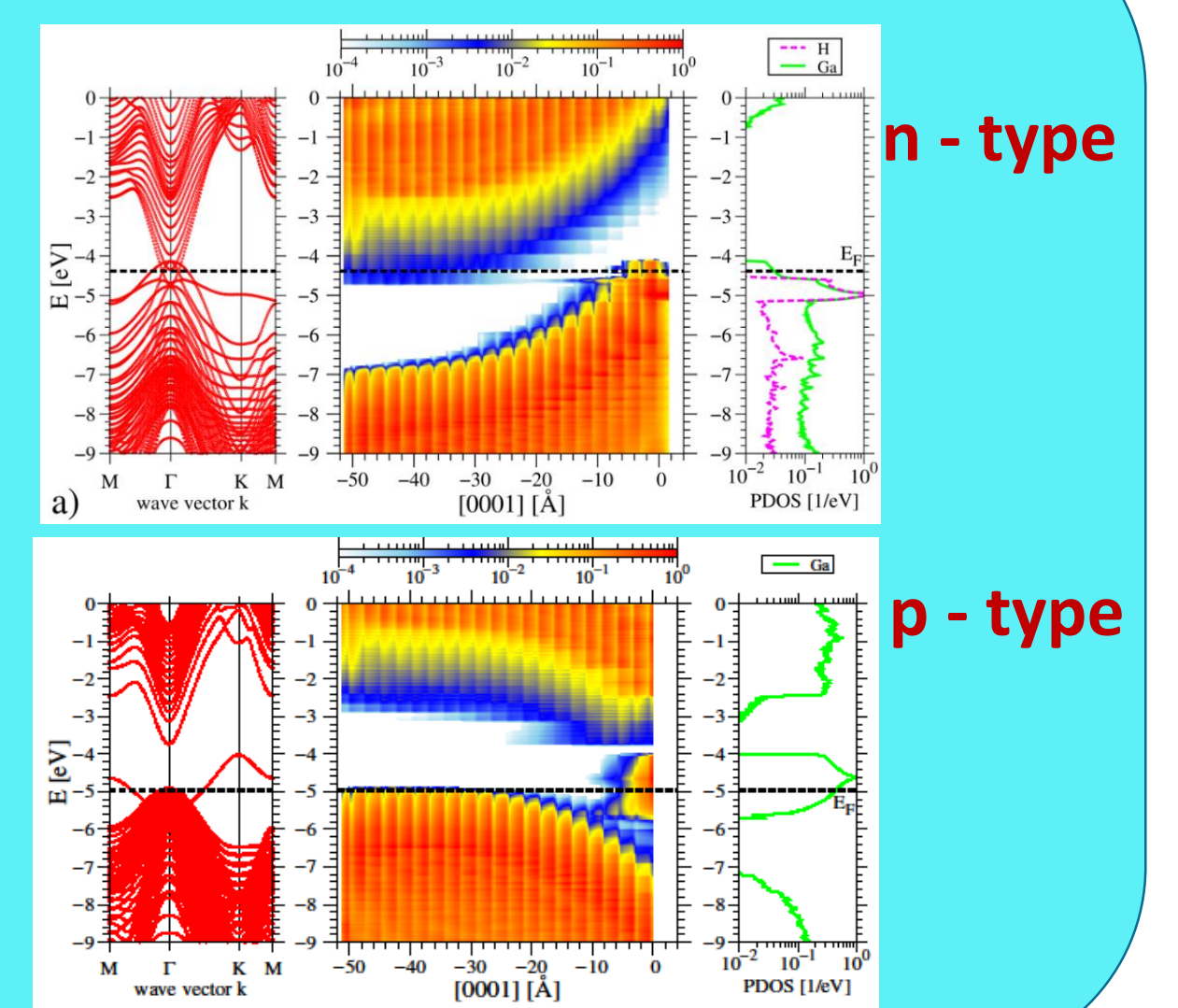
- In-plane and c-axis adjacent averaging
- Smoothed potential profiles
- Charges & dipoles are obtained

### Real space band visualization



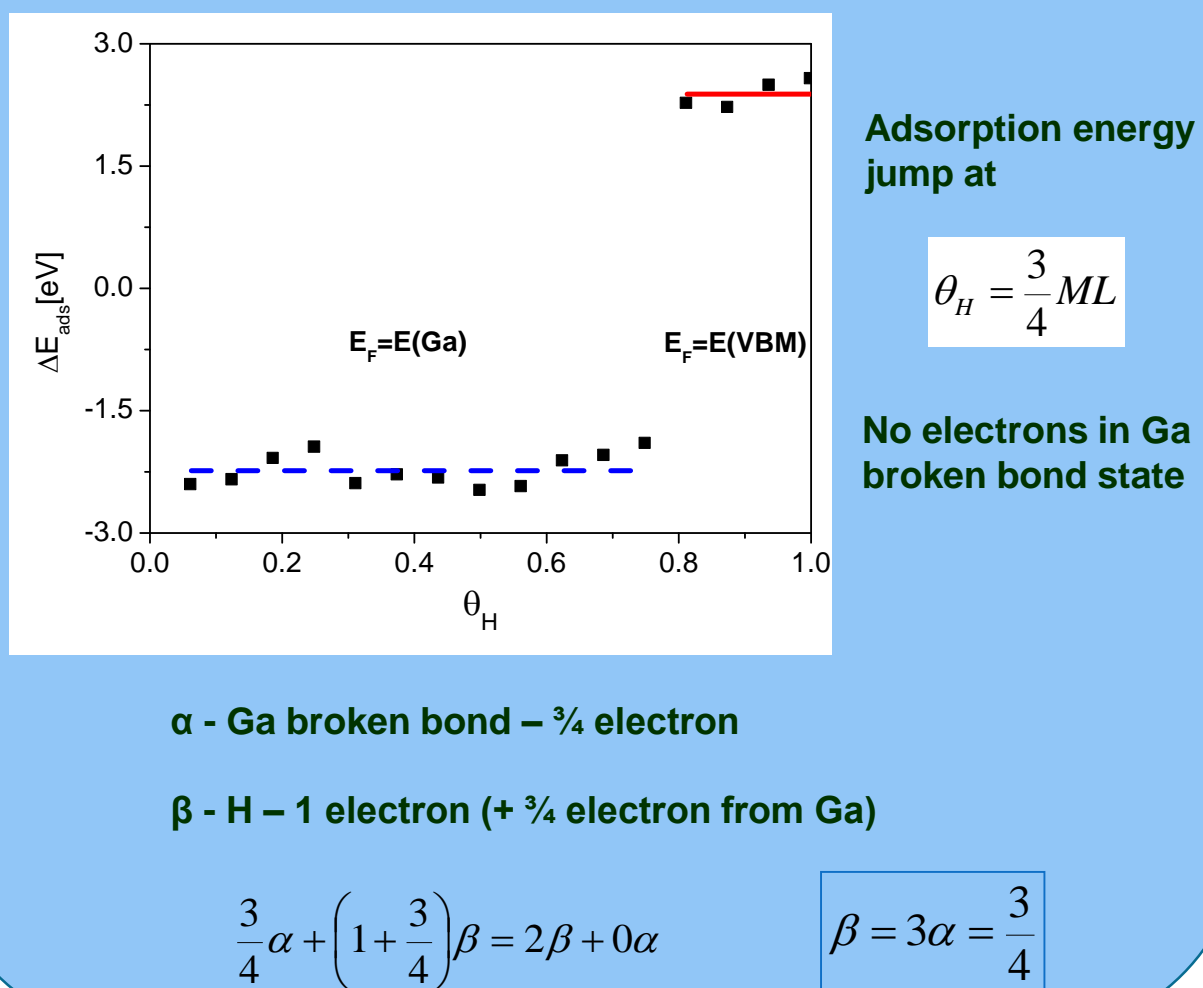
- Fields in the slabs
- Charged surface states
- Fermi level pinning

### Doping- Fermi level pinning

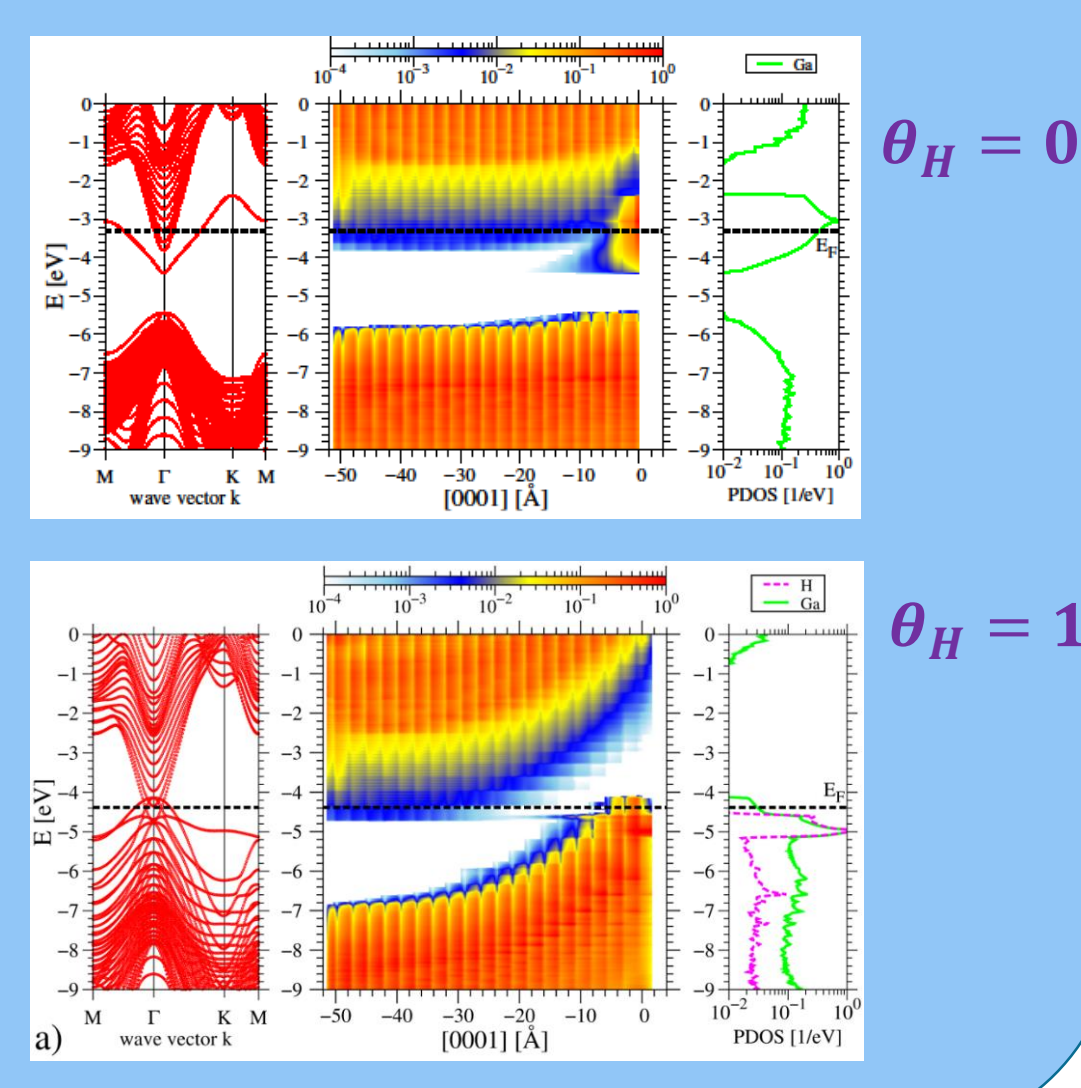


## New results

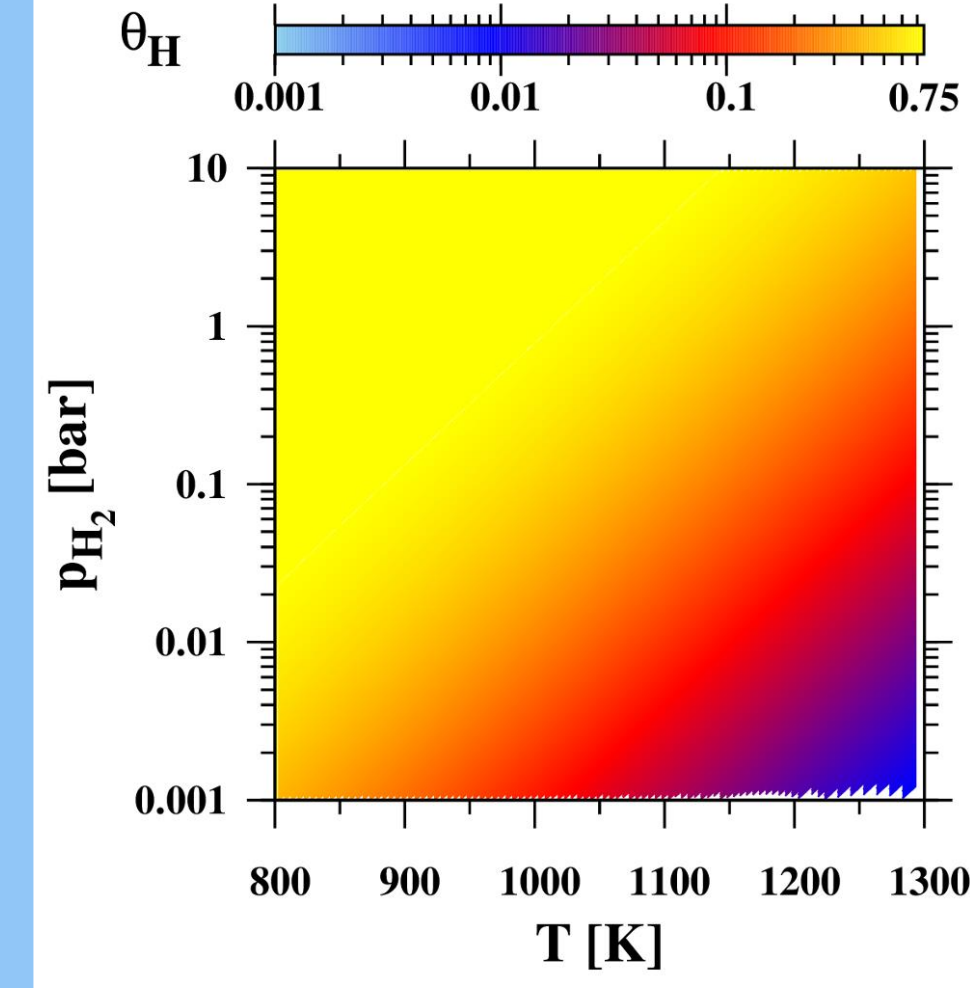
### Charge contribution to adsorption energy: H at GaN(0001) surface



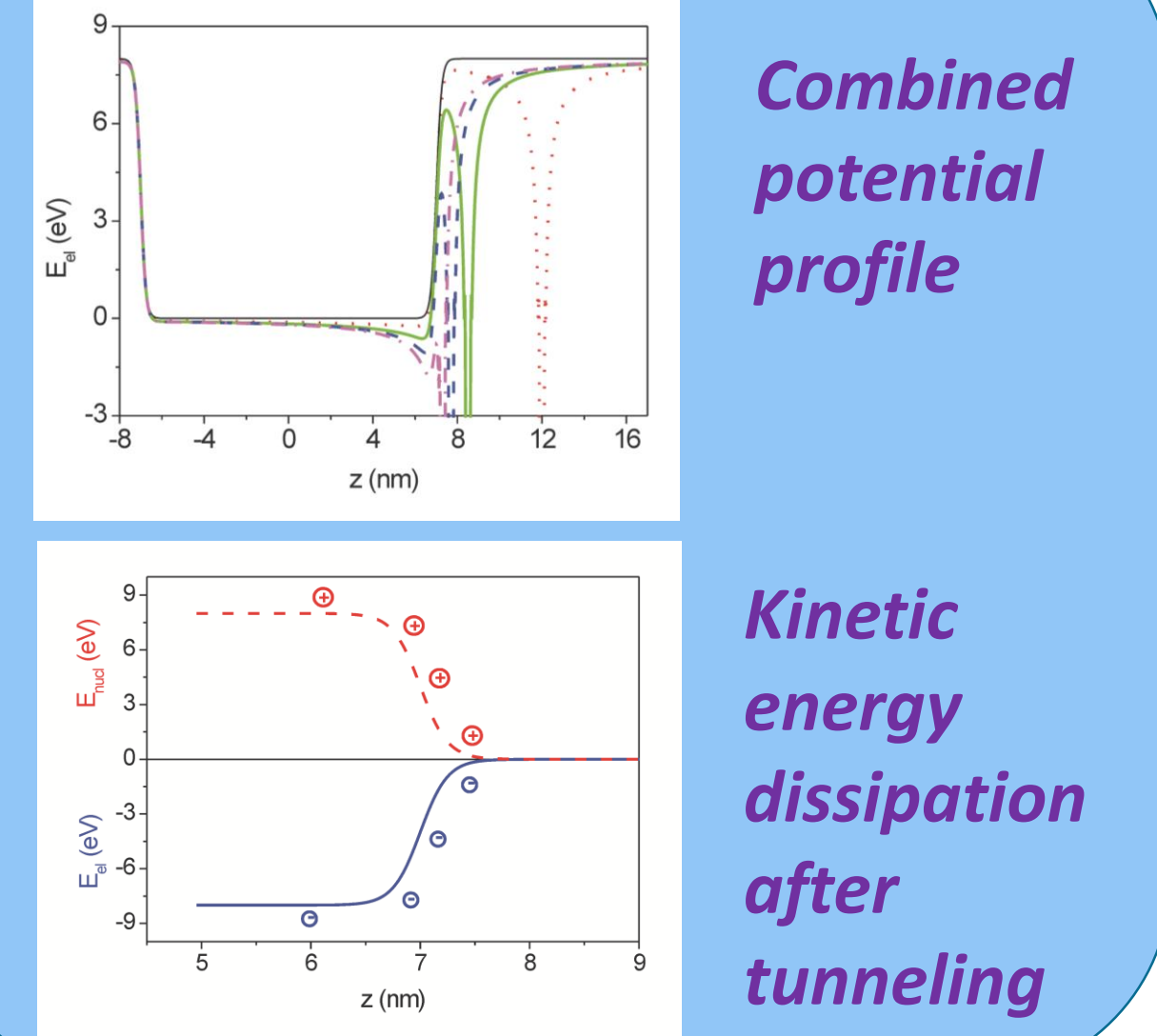
### Fermi level pinning



### Phase diagrams – H at GaN(0001) surface

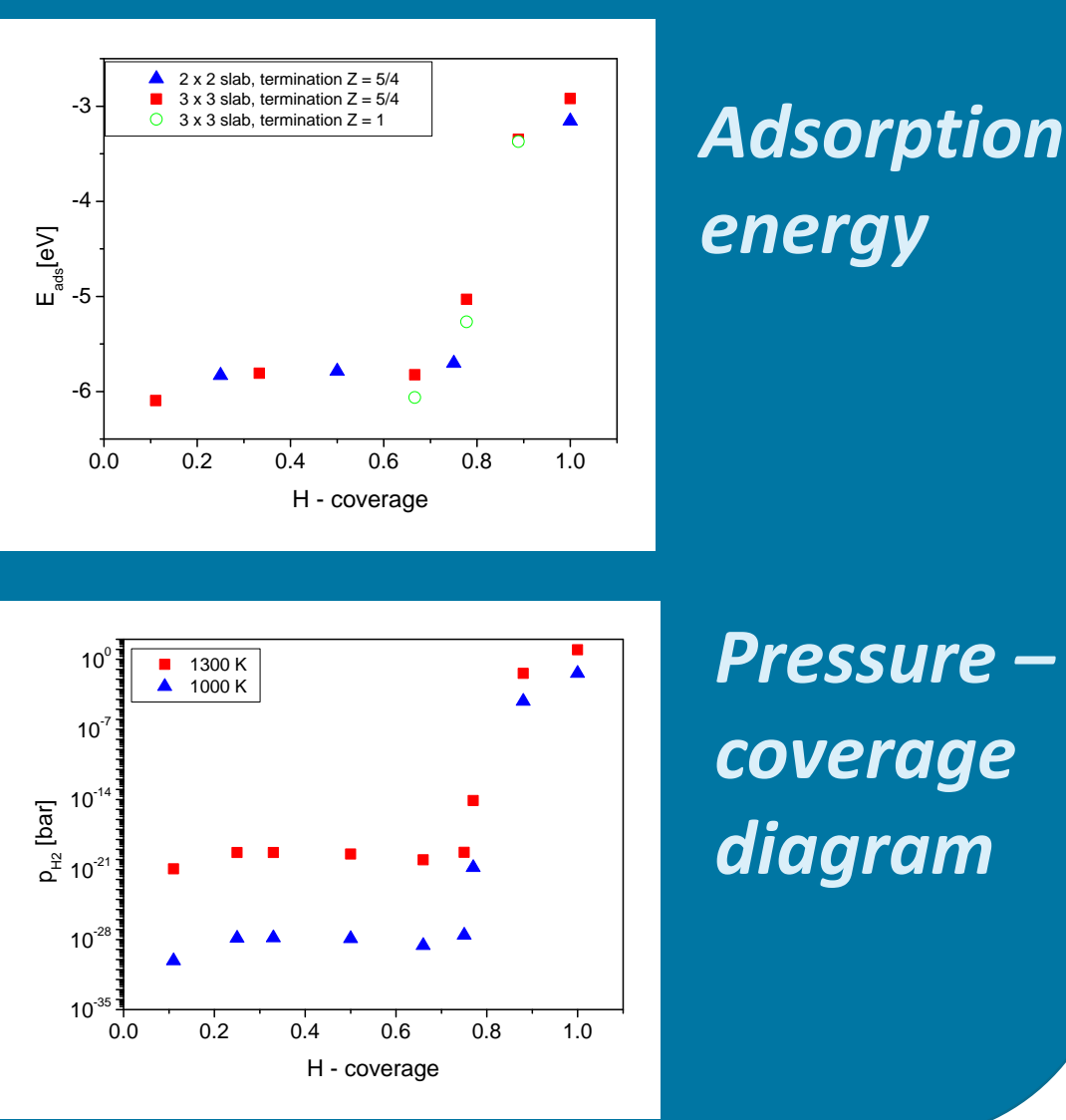


### Thermalization by electron tunneling

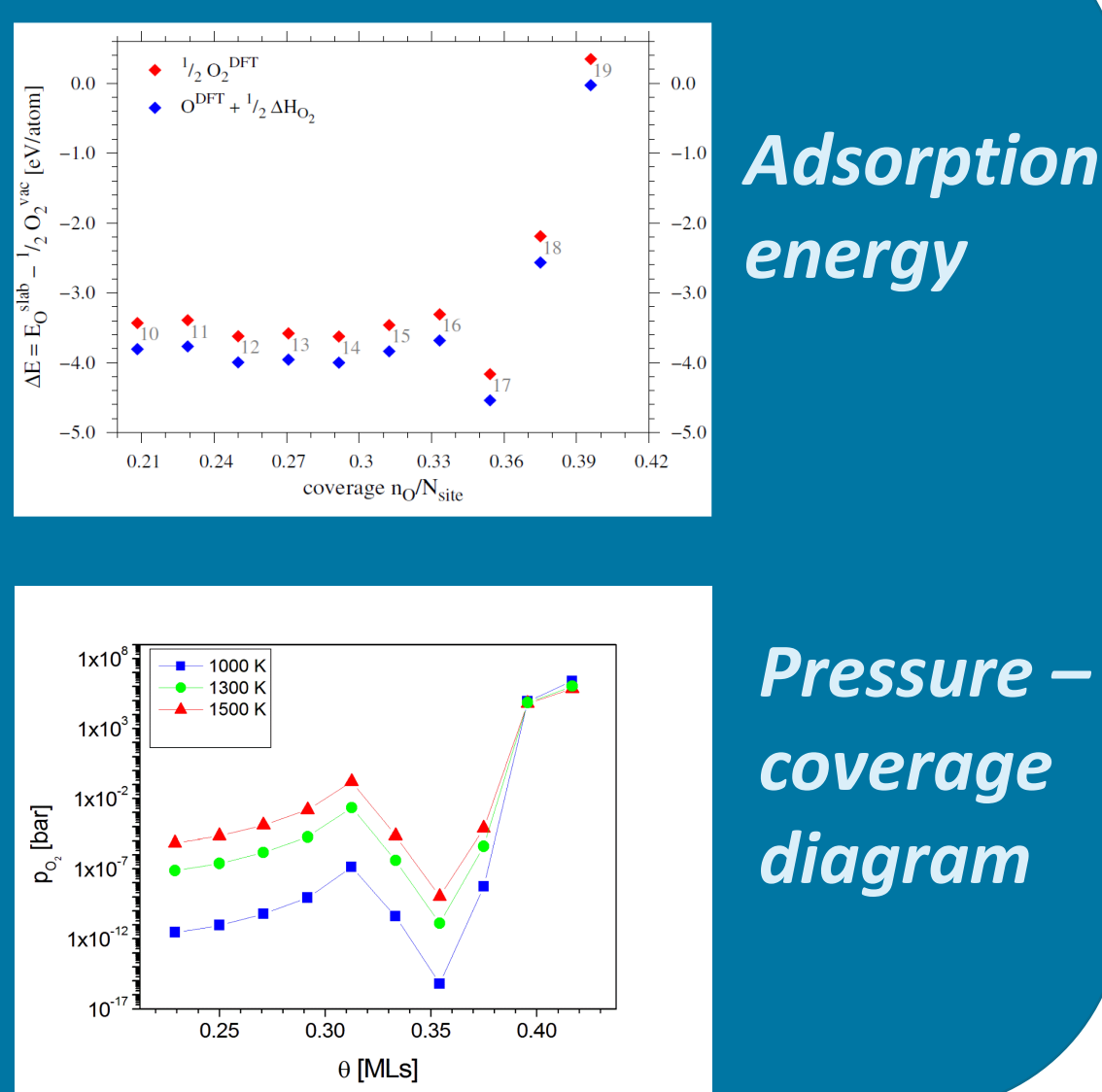


## Semiconductor surfaces & adsorbates

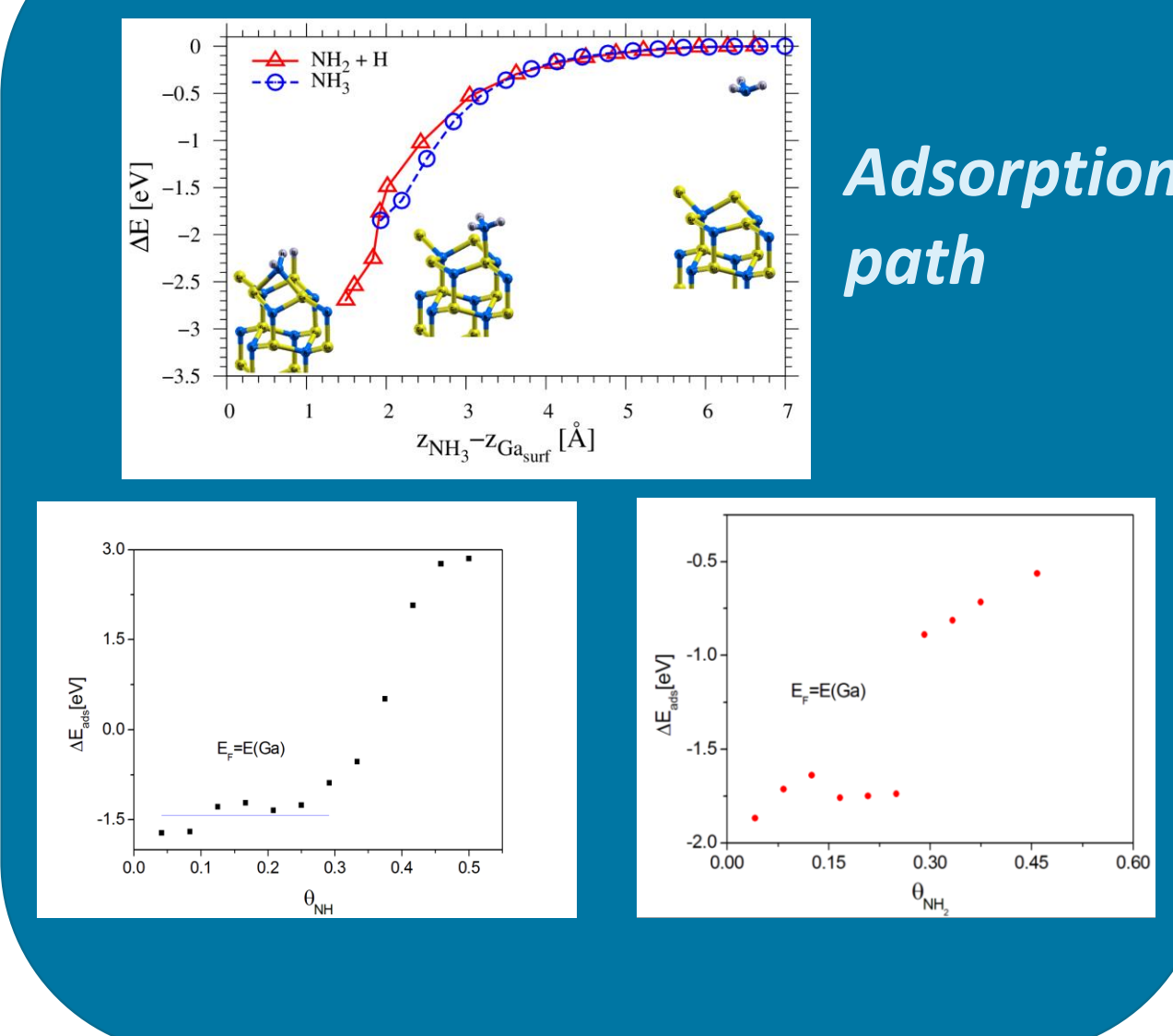
### H at GaN(000-1) surface



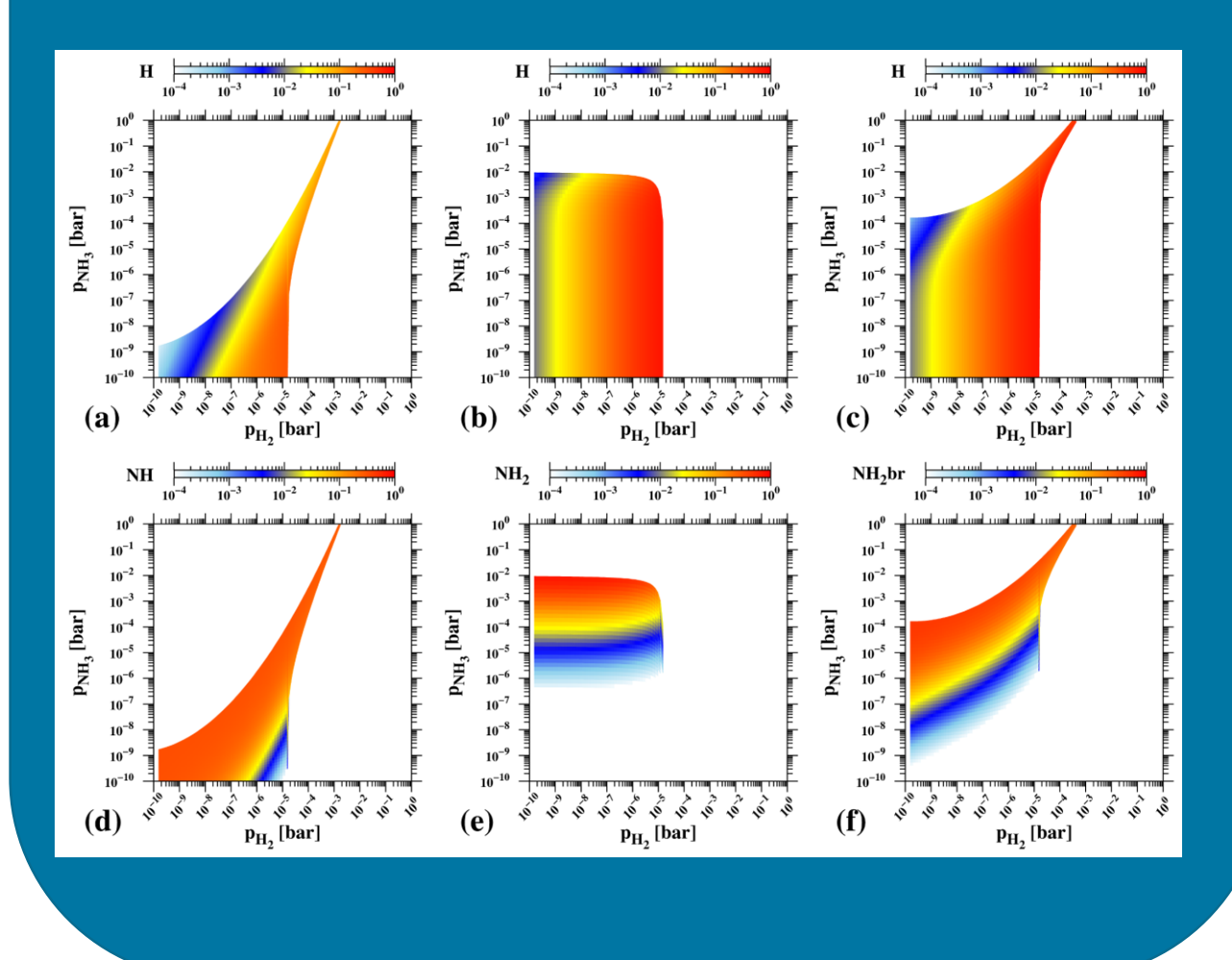
### Oxygen at GaN(0001) surface



### Ammonia at GaN(0001) surface

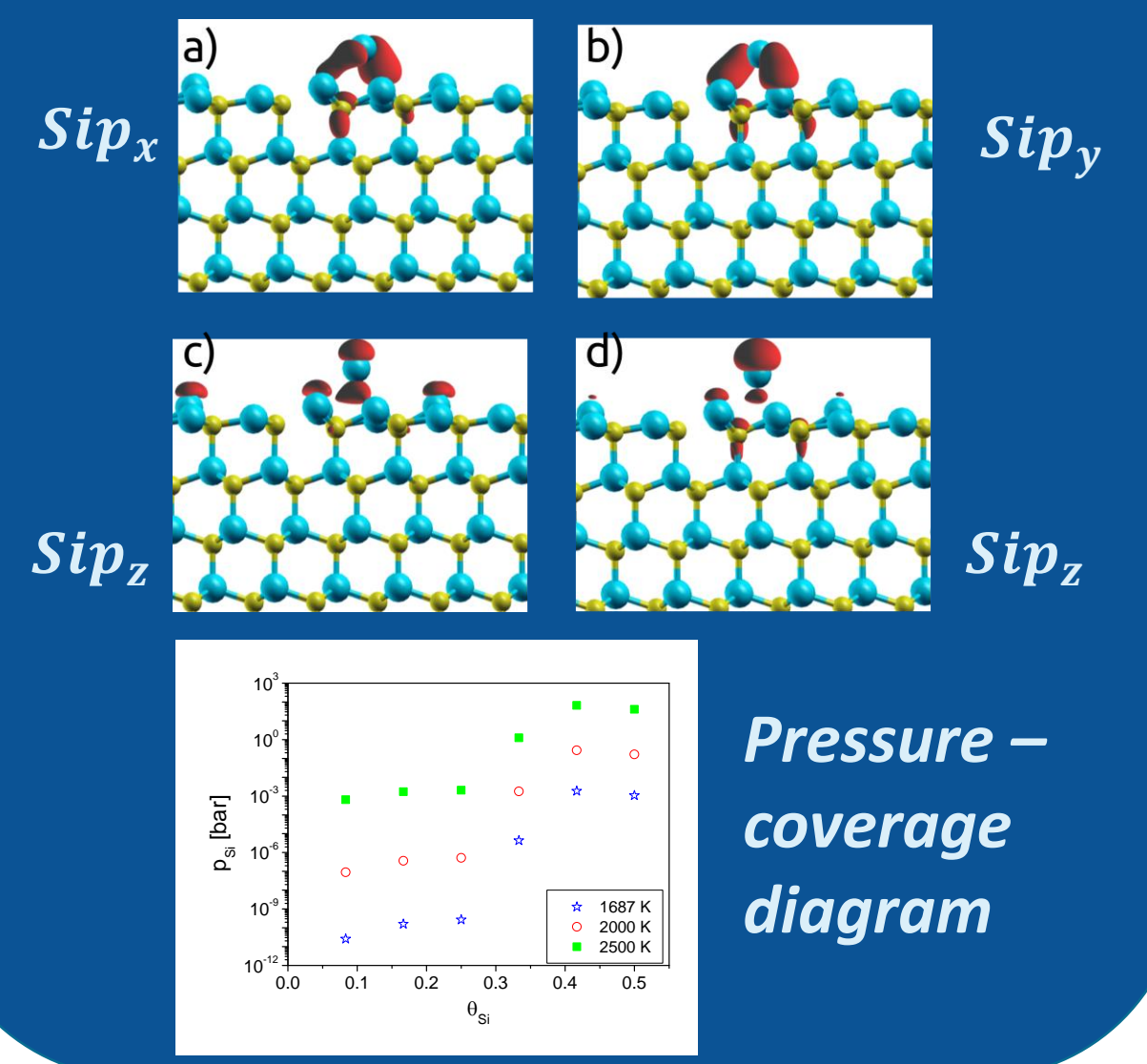


### Ammonia at GaN(0001) surface H and N related radicals coverage

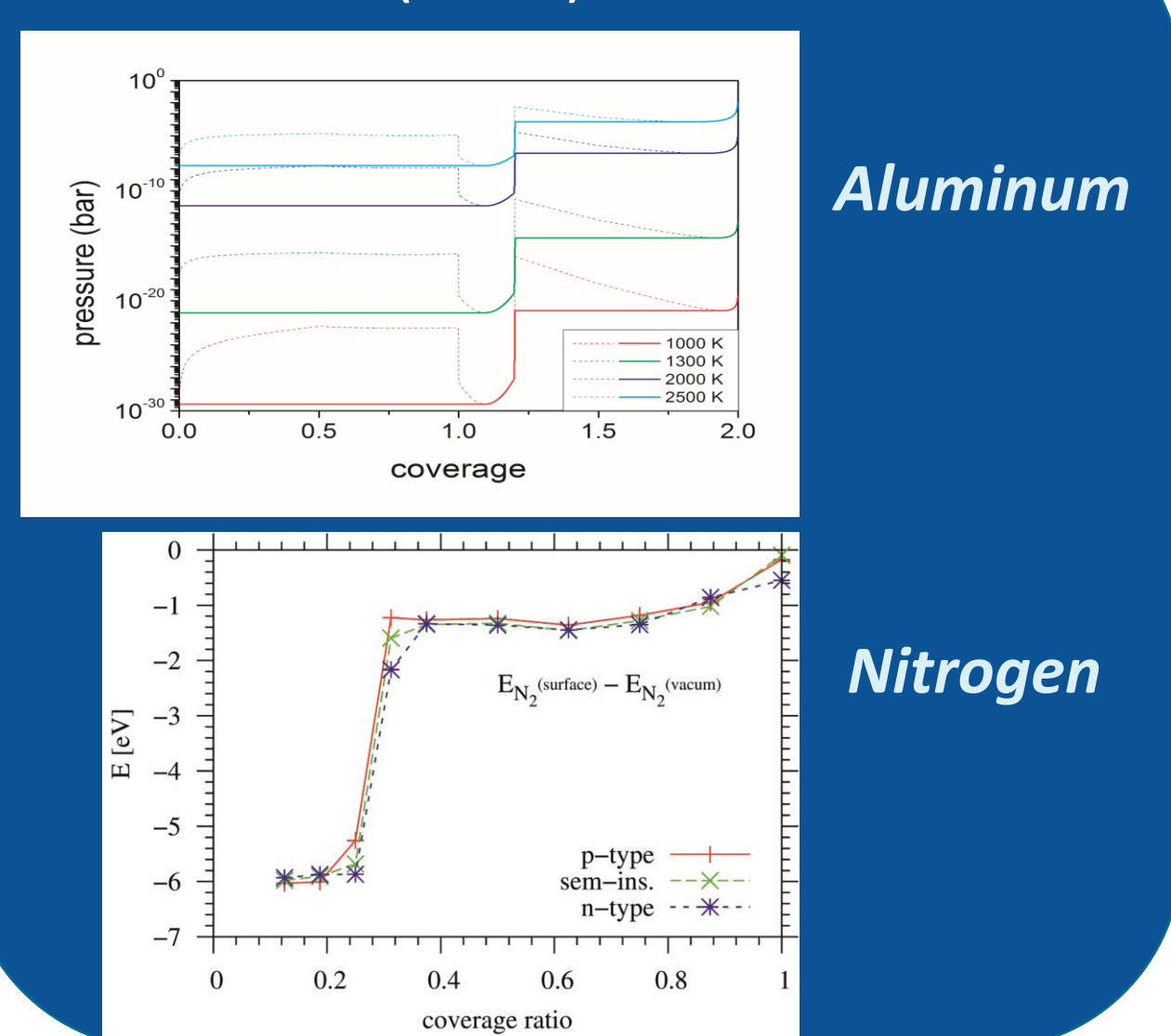


## Semiconductor surfaces & adsorbates

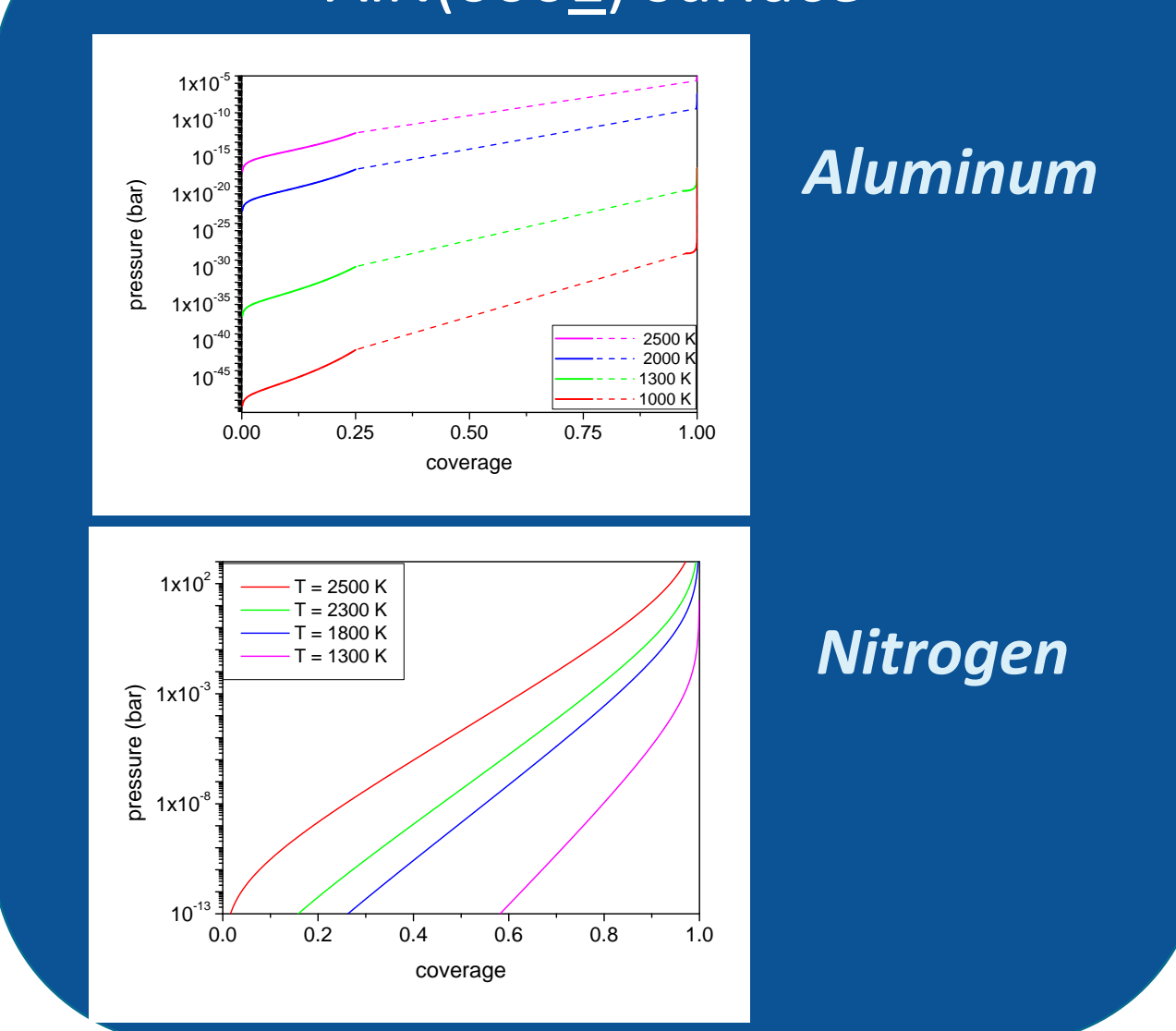
### SiC surface



### AlN(0001) surface



### AlN(0001) surface



## Summary

- Laplace correction for slab simulations
- Averaging procedures for *ab initio* data
- Doping in surface slab simulations
- Charge transfer contribution to adsorption energy
- Adsorbate thermalization model
- Thermal contribution to free energy of the adsorbate
- Pressure-coverage diagrams for number of semiconductor surfaces

Use this QR code to see the poster on-line

